

# ACTIVATION and BACKGROUND RADIATION IN THE HALL WITH SoLID



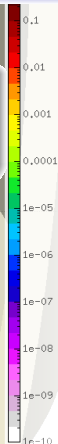
-1000

-1000

1000

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Lorenzo Zana  
The University of Edinburgh  
August 6 2013



## 1 Estimated Radiation damage in the Hall

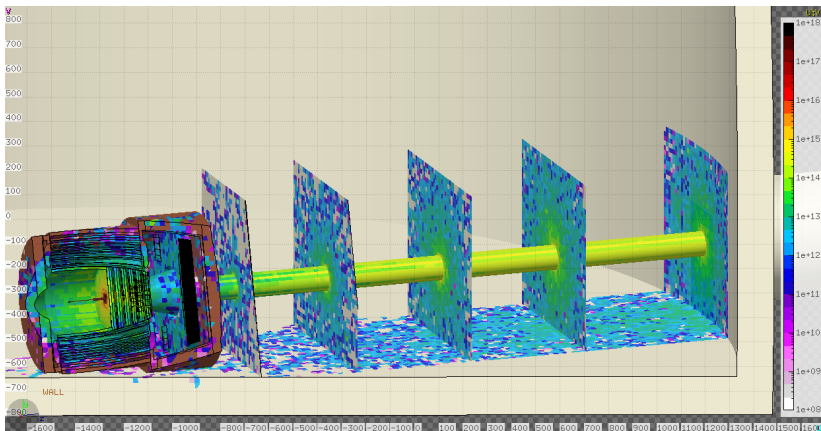
- PVDIS  $^2H$
- SIDIS  $^3He$

## 2 Power deposited and Activation

- PVDIS  $^2H$
- SIDIS  $^3He$

# 1MeV Neutron equivalent damage on Silicon

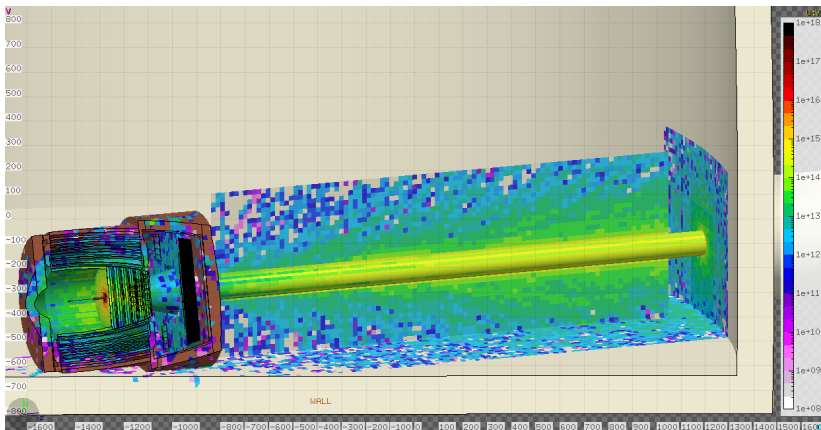
PVDIS config 2000h with  $100\mu\text{A}$ : from TG  $\Delta z = 6m$ ,  $\Delta z = 10m$ ,  
 $\Delta z = 15m$ ,  $\Delta z = 20m$





# 1MeV Neutron equivalent damage on Silicon

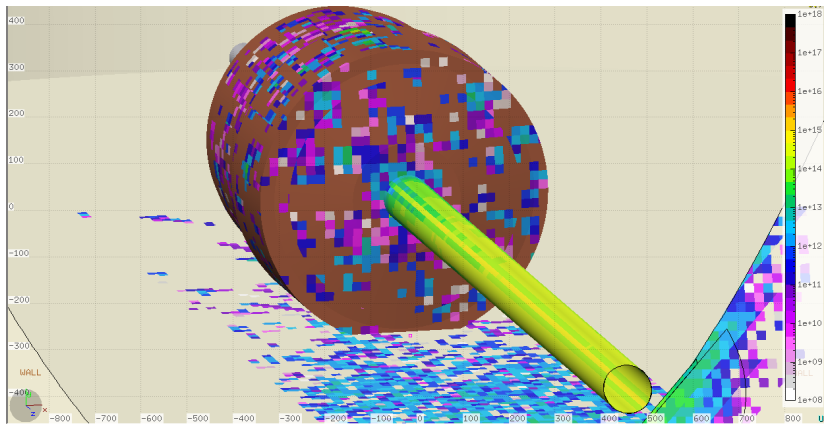
PVDIS config 2000h with  $100\mu A$ : View on the plane  $x = 0$





# 1MeV Neutron equivalent damage on Silicon

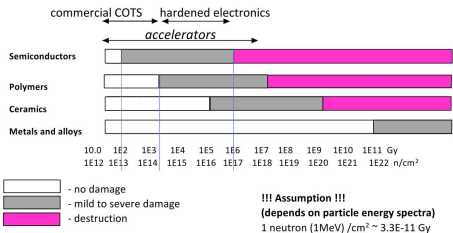
PVDIS config 2000h with  $100\mu\text{A}$ : View of the back of the magnet





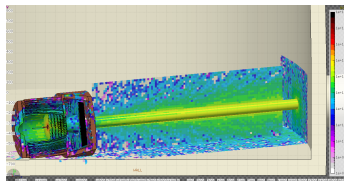
# 1MeV Neutron equivalent damage on Silicon

## Tolerance of different material



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PVDIS config 2000h with  
100μA



# 1MeV Neutron equivalent damage on Silicon

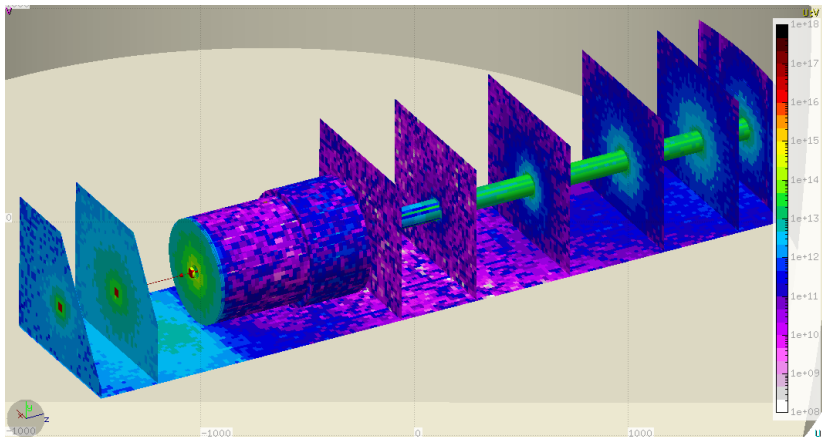
## PVDIS

- Estimate of radiation damage in the Hall with the SoLID spectrometer and the PVDIS configuration. The leading part of radiation present in the Hall for the SoLID spectrometer is leaking through the downstream part of the beam-line assembly. In this plot is shown the 1MeV Neutron equivalent flux per  $cm^2$  on the volumes surfaces estimated for 2000h of continuous running with a beam current of  $100\mu A$  (This is the expected beam-time with the PVDIS configuration).
- The level of radiation leaking increases as one moves farther from the target, reaching a maximum  $\leq 10^{15} \frac{N_{1MeV}}{cm^2}$ . These levels of radiation is on the “mild to severe” damage range for commercial semiconductors



# 1MeV Neutron equivalent damage on Silicon

SIDIS config 3000h with  $15\mu\text{A}$ :  $\Delta z = -10\text{m}$ ,  $\Delta z = -6\text{m}$ ,  
 $\Delta z = 6\text{m}$ ,  $\Delta z = 10\text{m}$ ,  $\Delta z = 15\text{m}$ ,  $\Delta z = 20\text{m}$ ,  $\Delta z = 24\text{m}$

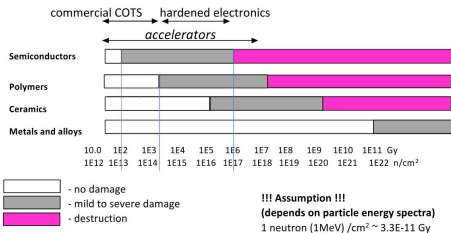






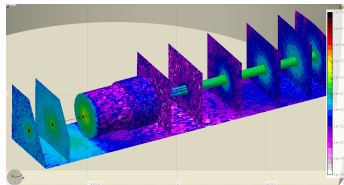
# 1MeV Neutron equivalent damage on Silicon

## Tolerance of different material



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SIDIS config 3000h with  
15μA





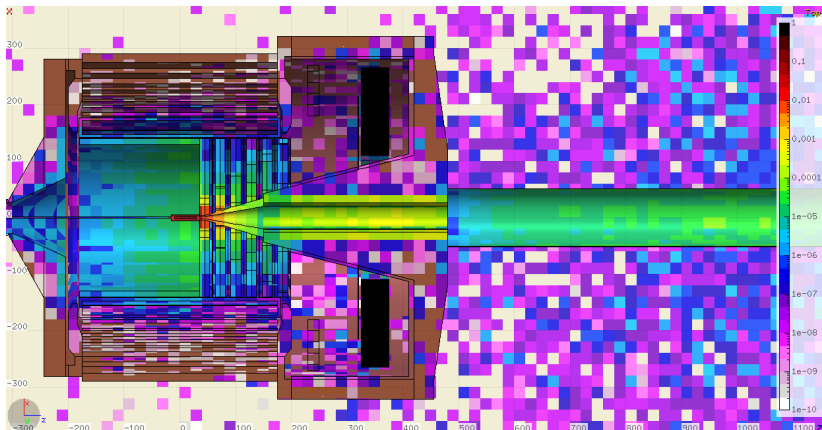
# 1MeV Neutron equivalent damage on Silicon

## SIDIS

- Estimate of radiation damage in the Hall with the SoLID spectrometer and the SIDIS  $^3\text{He}$  configuration. The leading part of radiation present in the Hall for the SoLID spectrometer is originating from the target area and the closer surface of the magnet. In this plot is shown the 1MeV Neutron equivalent flux per  $\text{cm}^2$  on the volumes surfaces estimated for 3000h of continuous running with a beam current of  $15\mu\text{A}$
- The level of radiation leaking increases as one moves farther from the target, reaching a maximum  $\leq 10^{15} \frac{N_{1\text{MeV}}}{\text{cm}^2}$ . These levels of radiation is on the “mild to severe” damage range for commercial semiconductors

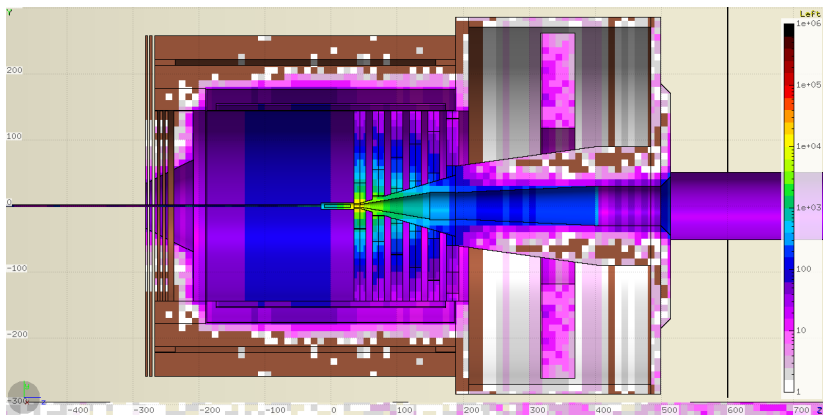
# Power deposited and Activation (Magnet Area)

Energy deposited (W) per  $\text{cm}^3$  for PVDIS configuration and Liquid Deuterium target



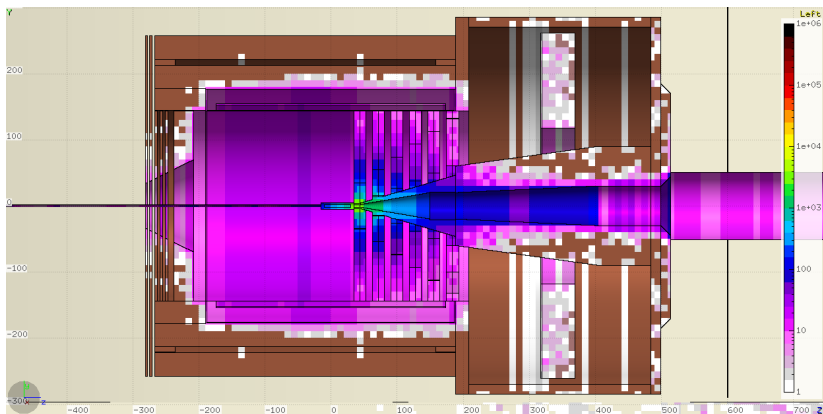
# Power deposited and Activation (Magnet Area)

Dose equivalent (mrem) per hour after 1 hour from beam exposure for PVDIS configuration and Liquid Deuterium target



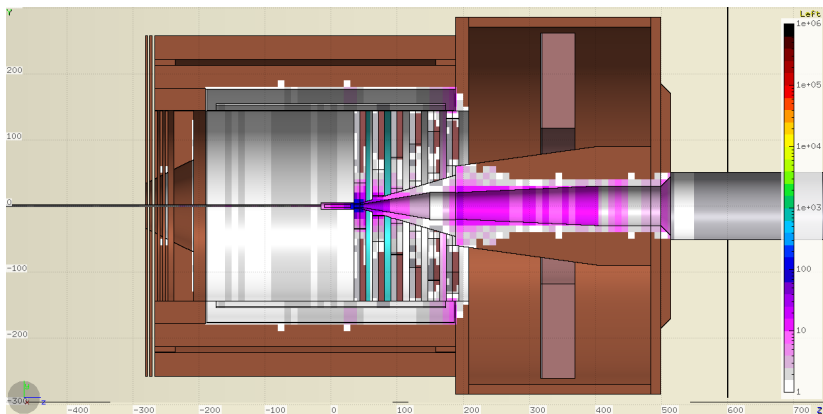
# Power deposited and Activation (Magnet Area)

Dose equivalent (mrem) per hour after 1day from beam exposure for PVDIS configuration and Liquid Deuterium target



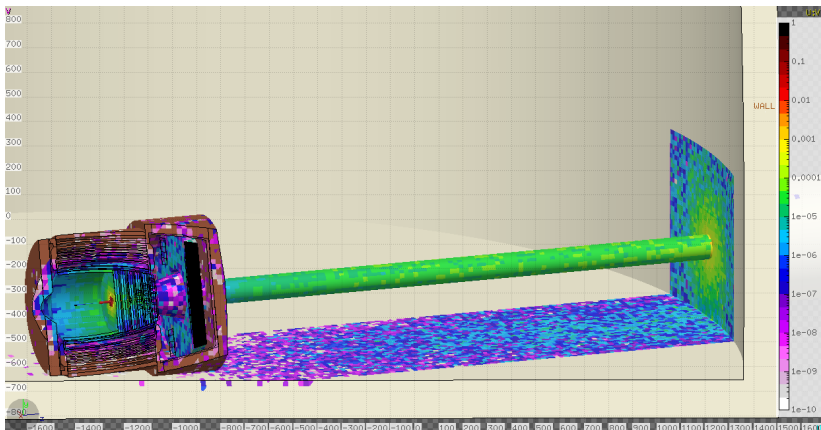
# Power deposited and Activation (Magnet Area)

Dose equivalent (mrem) per hour after 1 month from beam exposure for PVDIS configuration and Liquid Deuterium target



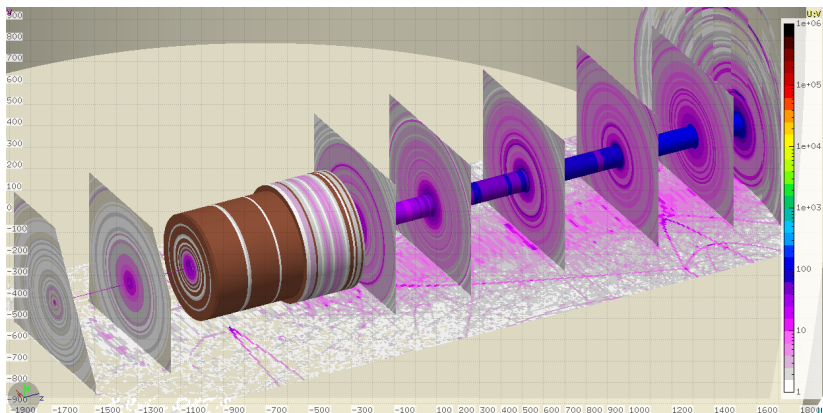
# Power deposited and Activation (Hall Area)

Energy deposited (W) per  $cm^3$  for PVDIS configuration and Liquid Deuterium target



# Power deposited and Activation (Hall Area)

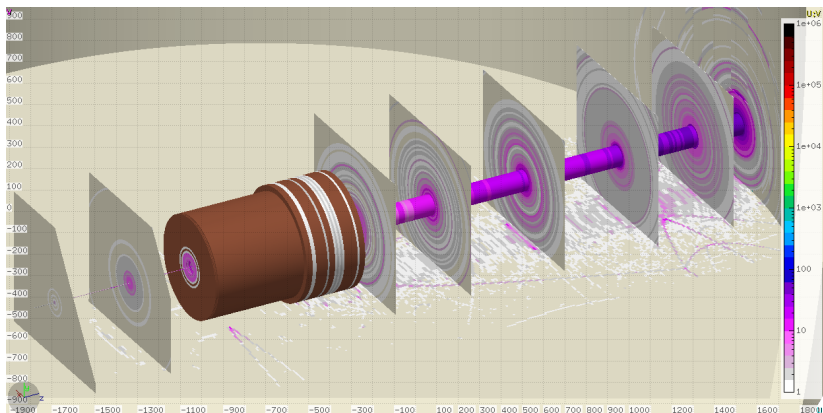
Dose equivalent (mrem) per hour after 1 hour from beam exposure for PVDIS configuration and Liquid Deuterium target





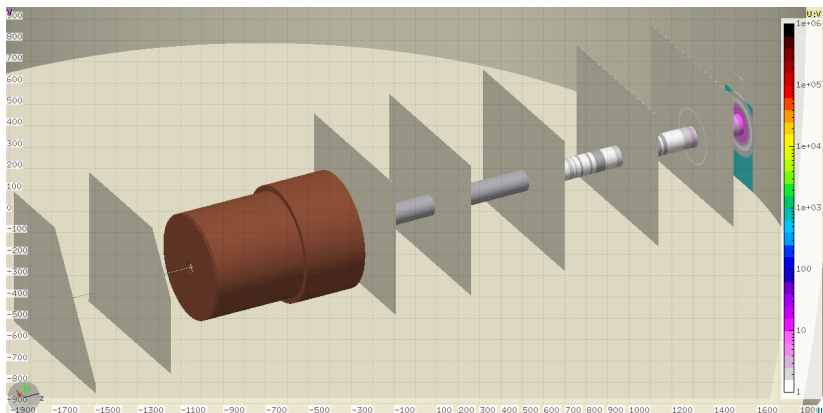
# Power deposited and Activation (Hall Area)

Dose equivalent (mrem) per hour after 1day from beam exposure for PVDIS configuration and Liquid Deuterium target



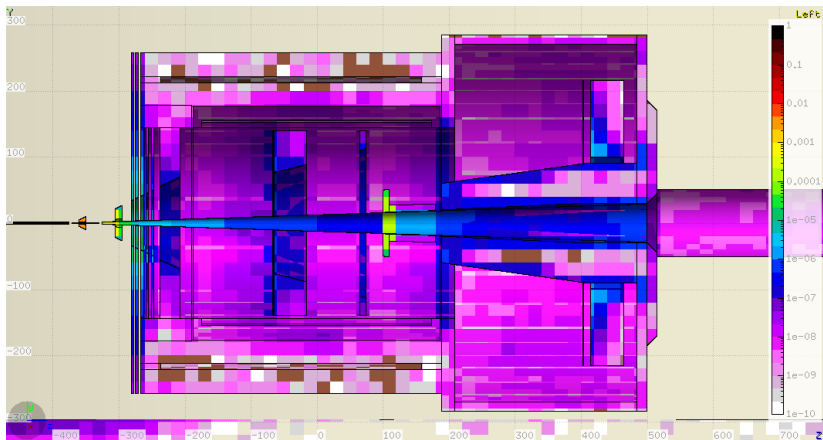
# Power deposited and Activation (Hall Area)

Dose equivalent (mrem) per hour after 1 month from beam exposure for PVDIS configuration and Liquid Deuterium target



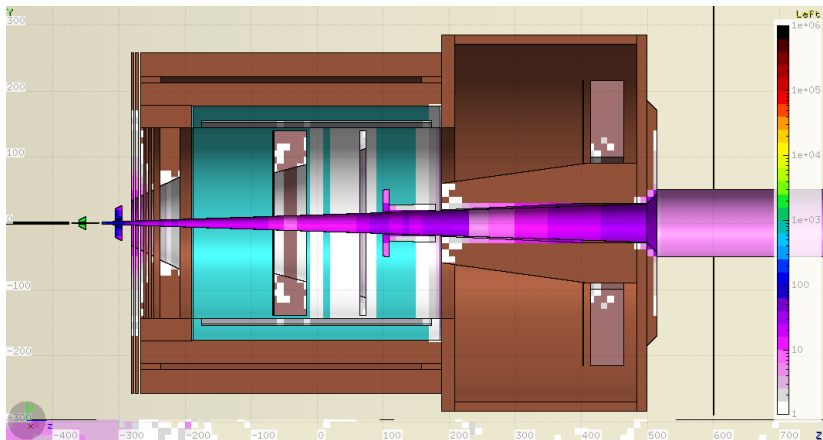
# Power deposited and Activation (Magnet Area)

Energy deposited (W) per  $cm^3$  for SIDIS configuration and  $^3He$  target



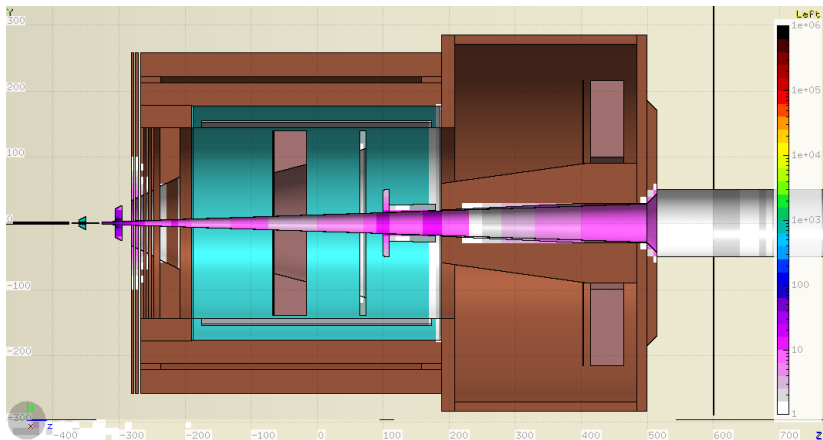
# Power deposited and Activation (Magnet Area)

Dose equivalent (mrem) per hour after 1 hour from beam exposure  
for SIDIS configuration and  $^3\text{He}$  target



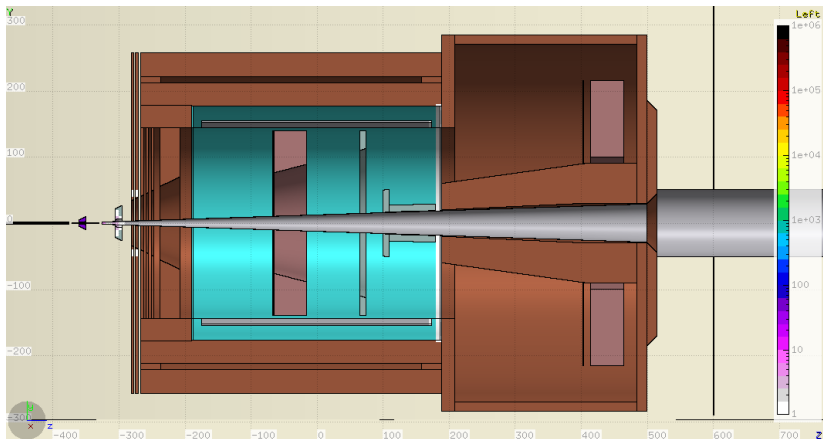
# Power deposited and Activation (Magnet Area)

Dose equivalent (mrem) per hour after 1day from beam exposure  
for SIDIS configuration and  ${}^3\text{He}$  target



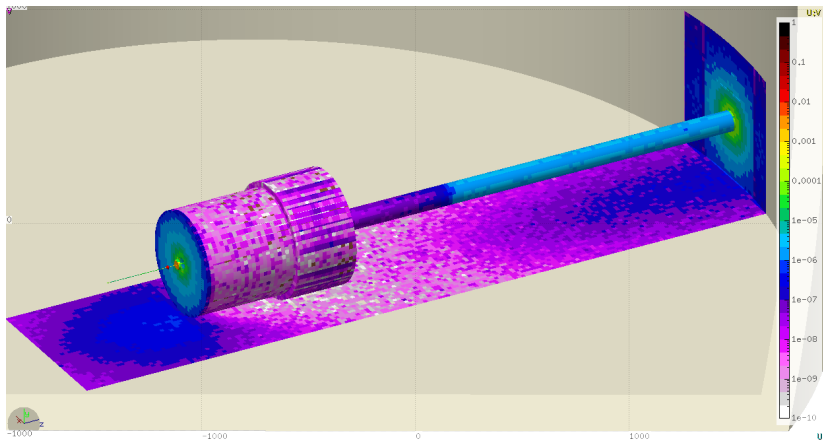
# Power deposited and Activation (Magnet Area)

Dose equivalent (mrem) per hour after 1 month from beam exposure for SIDIS configuration and  $^3\text{He}$  target



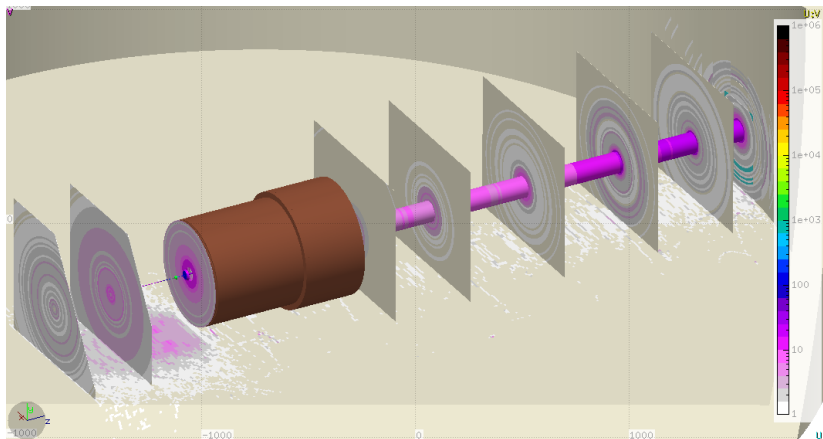
# Power deposited and Activation (Hall Area)

Energy deposited (W) per  $cm^3$  for SIDIS configuration and  $^3He$  target



# Power deposited and Activation (Hall Area)

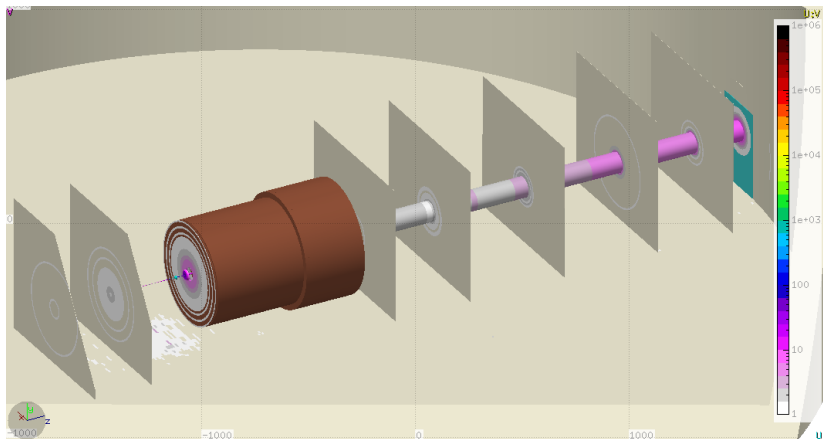
Dose equivalent (mrem) per hour after 1 hour from beam exposure for SIDIS configuration and  $^3\text{He}$  target





# Power deposited and Activation (Hall Area)

Dose equivalent (mrem) per hour after 1day from beam exposure for SIDIS configuration and  $^3\text{He}$  target



# Power deposited and Activation (Hall Area)

Dose equivalent (mrem) per hour after 1 month from beam exposure for SIDIS configuration and  $^3\text{He}$  target

